



ITW

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Tsao, Yi-Chang; et al.	)	Examiner:	Gabor, Otilia
Serial No.:	10/607,607	)	Art Unit:	2878
Filed:	June 27, 2003	)	Our Ref:	B-5136 621042-5
For:	"APPARATUS AND METHOD FOR INSPECTING CRYSTAL QUALITY OF A POLYSILICON FILM"	)	Date:	June 9, 2005
		)	Re:	<i>Amendment and Response</i>

AMENDMENT AND RESPONSE

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

This is in reply to the non-final Office Action mailed on March 10, 2005, an initial response to which is due no later than

June 10, 2005.

Please amend the above-identified application as described below and consider the following remarks. **All amendments and remarks herein are made without prejudice.**

**Amendments to the Specification** begin on page 2 of this paper.

**Remarks/Arguments** begin on page 3 of this paper.